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| Search Notes  | Application/Control No. 10580401 | Applicant(s)/Patent Under Reexamination CHEN ET AL. |
| | Examiner Awet Haile | Art Unit 2474 |

| SEARCHED | | | |
|----------|---------------------------------------|------------|----------|
| Class | Subclass | Date | Examiner |
| 370 | 395.2, 395.5, 252 | 10/31/2009 | MA |
| 370 | 231, 232, 233, 235, 236.1, 395.5, 468 | 5/7/2010 | A.H |
| Above | Updated | 9/30/2010 | A.H |

| SEARCH NOTES | | |
|---|------------|----------|
| Search Notes | Date | Examiner |
| East Search (updated) | 2/17/2009 | MA |
| Inventor's/Asignee's Search | 10/31/2009 | MA |
| NPL(IEEE, Books and so) | 10/31/2009 | MA |
| PLUS Search | 10/31/2009 | MA |
| Google/patents/scholar | 10/31/2009 | Ma |
| East text search | 5/7/2010 | A.H |
| East class/subclass limited search 370/395.5, 370/236.1 | 5/7/2010 | A.H |
| Inventor's search | 5/7/2010 | A.H |
| East class/subclass limited search 370/395.5, 370/236.1 | 9/30/2010 | A.H |
| Inventor's search | 9/30/2010 | A.H |
| East text search | 9/30/2010 | A.H |

| INTERFERENCE SEARCH | | | |
|---------------------|----------|------|----------|
| Class | Subclass | Date | Examiner |
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